Field Emission Gun - Transmission Electron Microscope - 200kV

Sample Analysis Request Form

| User Details: | |
|---------------------------------|-----------------------------|
| Name of the User: | |
| Department: | |
| Email ID: | Mobile No.: |
| Name of Guide/PI: | |
| Guide/PI Email ID: | |
| Analysis mode: | ation |
| Imaging: TEM, HRTEM, and Diffra | CTION |
| Accelerating voltage | 120kV OR 200kV |
| Sample information: | |
| Number of samples | One OR Two Max. 2 samples) |
| Detailed description of samples | |
| Expected Morphology | |

Instructions for user:

- The users will be informed about their date and time of slot by email. The FEG-TEM grids can be collected from the lab after getting the slot for the analysis.
- The user should come for FEG-TEM analysis with prepared samples.
- The upper limit for the number of samples acceptable per slot is Two (2).
- Please contact us on fegtemlab@iitb.ac.in or Phone No.6865 for any query related to your FEG-TEM analysis.

Analysis charges:

Imaging (TEM, HR-TEM, Diffraction): Rs.875/- Per sample